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# **STP16NK65Z STB16NK65Z-S**

# N-CHANNEL 650V - 0.38Ω - 13A TO-220 / I<sup>2</sup>SPAK Zener - Protected SuperMESH™ MOSFET

**Table 1: General Features** 

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>	Pw
STP16NK65Z	650 V	< 0.50 Ω	13 A	190 W
STB16NK65Z-S	650 V	< 0.50 Ω	13 A	190 W

- TYPICAL  $R_{DS}(on) = 0.38\Omega$
- EXTREMELY HIGH dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- GATE CHARGE MINIMIZED
- VERY LOW INTRINSIC CAPACITANCES
- VERY GOOD MANUFACTURING REPEATIBILITY

#### **DESCRIPTION**

The SuperMESH™ series is obtained through an extreme optimization of ST's well established stripbased PowerMESH™ layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage MOSFETs including revolutionary MDmesh™ products.

#### **APPLICATIONS**

- HIGH CURRENT, HIGH SPEED SWITCHING
- IDEAL FOR OFF-LINE POWER SUPPLIES

Figure 1: Package

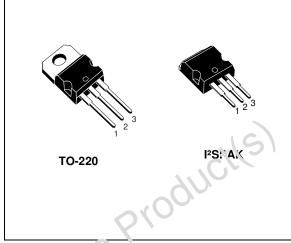


Figure 2: Interval Schematic Diagram

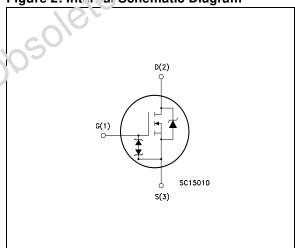


Table 2: Order Codes

	SALES TYPE	MARKING	PACKAGE	PACKAGING
7	STP16NK65Z	P16NK65Z	TO-220	TUBE
	STB16NK65Z-S	B16NK65Z	I <sup>2</sup> SPAK	TUBE

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**Table 3: Absolute Maximum ratings** 

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source Voltage (V <sub>GS</sub> = 0)	650	V
$V_{DGR}$	Drain-gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	650	V
V <sub>GS</sub>	Gate- source Voltage	± 30	V
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 25°C	13	A
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 100°C	8.19	А
I <sub>DM</sub> (*)	Drain Current (pulsed)	52	A
P <sub>TOT</sub>	Total Dissipation at T <sub>C</sub> = 25°C	190	W
	Derating Factor	1.51	W/°C
V <sub>ESD(G-S)</sub>	Gate source EDS (HBM-C=100pF, R=1.5kΩ)	6000	V
dv/dt (1)	Peak Diode Recovery voltage slope	4.5	V/ns
T <sub>j</sub> T <sub>stg</sub>	Operating Junction Temperature Storage Temperature	-55 to 150	°C

<sup>(\*)</sup> Pulse width limited by safe operating area

#### **Table 4: Thermal Data**

Rthj-case	Thermal Resistance Junction-case Max	0.66	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	62.5	°C/W
Tı	Maximum Lead Temperature For Soldering Purpose	300	°C

#### **Table 5: Avalanche Characteristics**

Symbol	Parameter	Max. Value	Unit
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by $T_j$ max)	13	Α
E <sub>AS</sub>	Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	350	mJ

### Table 6: Gate-Source Zener Diode

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
BV <sub>GSO</sub>	Gate-Source Breakdown Voltage	Igs=± 1mA (Open Drain)	30			V

#### PROTECTION FEATURES OF GATE-TO-SOURCE ZENER DIODES

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied fromgate to source. In this respect the Zener voltage ia appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

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<sup>(1)</sup>  $I_{SD} \le 13$  A,  $di/dt \le 200$  A/ $\mu$ s,  $V_{DD} \le V_{(BR)DSS}$ ,  $T_i \le T_{JMAX}$ 

### **ELECTRICAL CHARACTERISTICS** (T<sub>CASE</sub> =25°C UNLESS OTHERWISE SPECIFIED)

#### Table 7: On/Off

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0	650			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max Rating V <sub>DS</sub> = Max Rating, T <sub>C</sub> = 125 °C			1 50	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			±10	μΑ
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 100 \mu A$	3	3.75	4.5	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	$V_{GS} = 10V, I_D = 6.5 A$		0.38	0.50	Ω

#### **Table 8: Dynamic**

	<del> </del>	t		1		
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (1)	Forward Transconductance	$V_{DS} = 15 V_{,} I_{D} = 6.5 A$		12	4	S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$		2750 275 60	Cili	pF pF pF
Coss eq. (*)	Equivalent Output Capacitance	$V_{GS} = 0V$ , $V_{DS} = 6.5 V$ to 520 V	01	188		pF
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$V_{DD} = 325 \text{ V, } I_D = 6.5 \text{ A}$ $R_G = 4.7\Omega \text{ V}_{GS} = 10 \text{ V}$ (see Figure 17)	3	25 25 68 17		ns ns ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 520 \text{ V}, I_{D} = 13 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see Figure 20)		89 18 45		nC nC nC

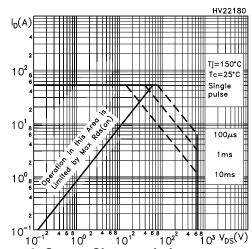
#### **Table 9: Source Drain Diode**

Symbol	pol Parameter Test Conditions		Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> (2)	Source-drain Current Source-drain Current (pulsed)				13 52	A A
V <sub>SD</sub> (1)	Forward On Voltage	I <sub>SD</sub> = 13 A, V <sub>GS</sub> = 0			1.6	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 13 \text{ A, di/dt} = 100 \text{ A/µs,} \ V_{DD} = 100 \text{ V, T}_{j} = 25^{\circ}\text{C} \ (\text{see Figure 18})$		500 5.2 21		ns μC A
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 13 \text{ A, di/dt} = 100 \text{ A/µs,} \ V_{DD} = 100 \text{ V, T}_{j} = 150 ^{\circ}\text{C} \ (\text{see Figure 18})$		615 7 22.5		ns μC A

<sup>(1)</sup> Pulsed: Pulse duration = 300µs, duty cycle 1.5%

<sup>(2)</sup> Pulse width limited by safe operating area (\*) C<sub>oss eq.</sub> is defined as a constant equivalent capacitance giving the same charging time as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DSS</sub>

Figure 3: Safe Operating Area



**Figure 4: Output Characteristics** 

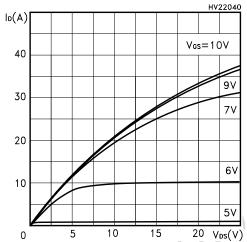


Figure 5: Transconductance

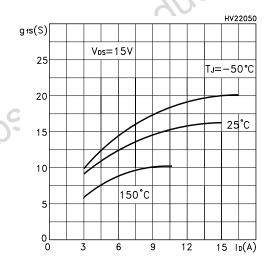
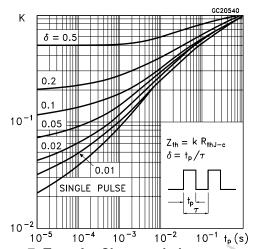


Figure 6: Thermal Impedance



**Figure 7: Transfer Characteristics** 

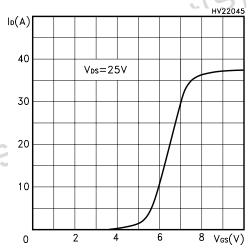
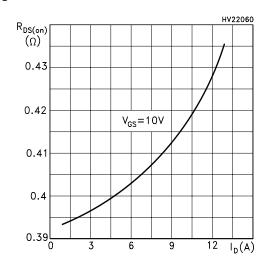


Figure 8: Static Drain-source On Resistance



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Figure 9: Gate Charge vs Gate-source Voltage

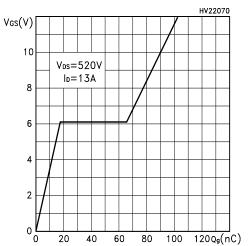


Figure 10: Normalized Gate Thereshold Voltage vs Temperature

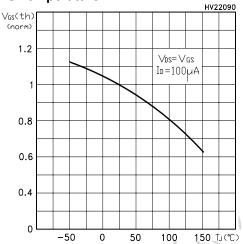


Figure 11: Dource-Drain Diode Forward Characteristics

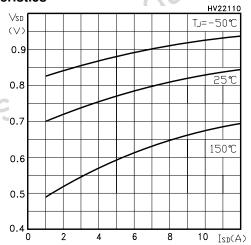


Figure 12: Capacitance Variations

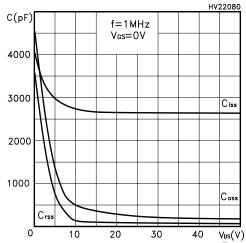


Figure 13: Normalized On Resistance vs Temperature

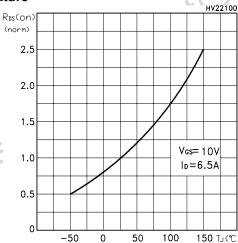


Figure 14: Normalized BVdss vs Temperature

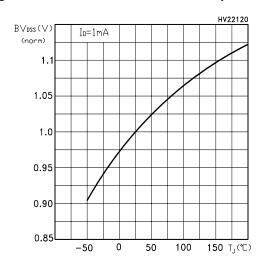
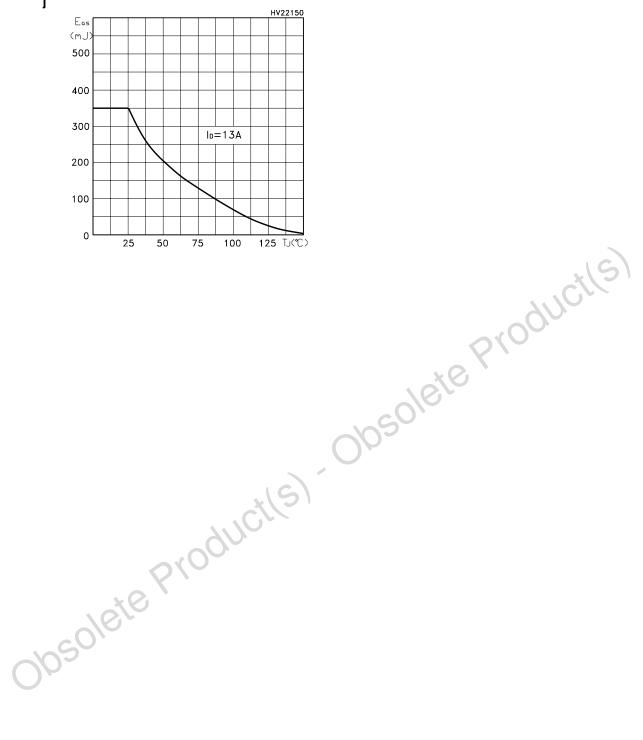


Figure 15: Avalanche Energy vs Starting Tj



**\7**/<sub>0</sub>

Figure 16: Unclamped Inductive Load Test Circuit

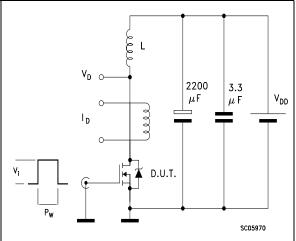
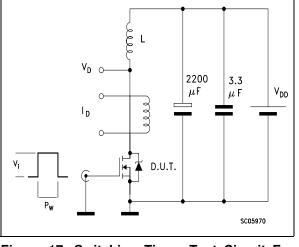


Figure 17: Switching Times Test Circuit For Resistive Load



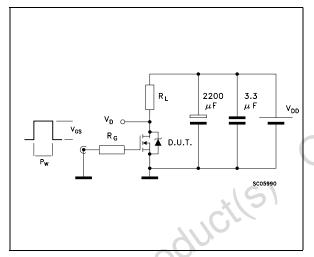


Figure 18: Test Circuit For Inductive Load Switching and Diode Recovery Times

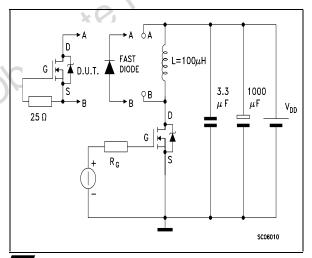


Figure 19: Unclamped Inductive Wafeform

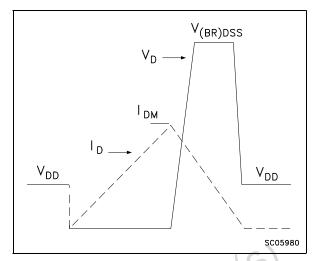
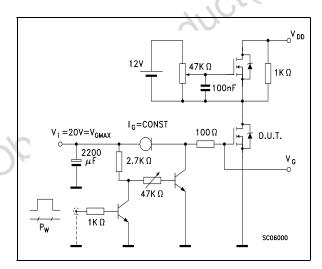


Figure 20: Gate Charge Test Circuit



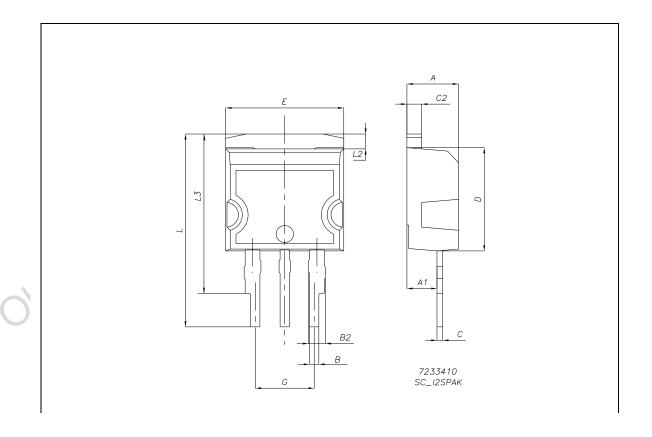
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: <a href="https://www.st.com">www.st.com</a>

Obsolete Product(s) - Obsolete Product(s)

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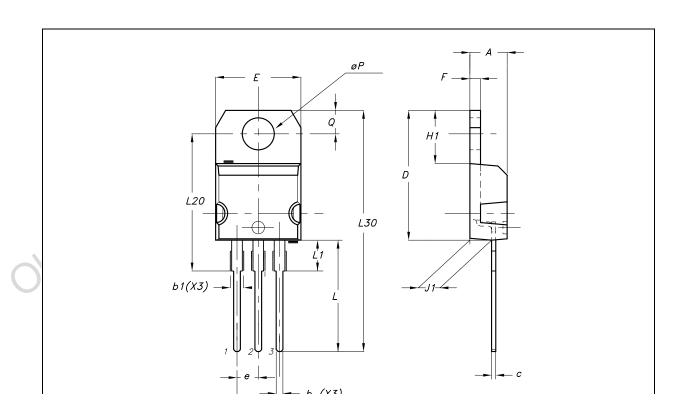
# I<sup>2</sup>SPAK MECHANICAL DATA

DIM.	mm.				inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
A1	2.49		2.69	0.098		0.106
В	0.70		0.93	0.027		0.037
B2	1.14		1.70	0.045		0.067
С	0.45		0.60	0.018		0.024
C2	1.23		1.36	0.048		0.053
D	8.95		9.35	0.352		0.368
E	10.00		10.40	0.394		0.409
G	4.88		5.28	0.192		0.208
L	16.7		17.5	0.657		0.689
L2	1.27		1.4	0.05		0.055
L3	13.82		14.42	0.544		0.568



## **TO-220 MECHANICAL DATA**

DIM		mm.		inch			
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.	
Α	4.40		4.60	0.173		0.181	
b	0.61		0.88	0.024		0.034	
b1	1.15		1.70	0.045		0.066	
С	0.49		0.70	0.019		0.027	
D	15.25		15.75	0.60		0.620	
Е	10		10.40	0.393		0.409	
е	2.40		2.70	0.094		0.106	
e1	4.95		5.15	0.194		0.202	
F	1.23		1.32	0.048		0.052	
H1	6.20		6.60	0.244		0.256	
J1	2.40		2.72	0.094		0.107	
L	13		14	0.511		0.551	
L1	3.50		3.93	0.137		0.154	
L20		16.40			0.645		
L30		28.90			1.137		
øΡ	3.75		3.85	0.147		0.151	
Q	2.65		2.95	0.104		0.116	



**Table 10: Revision History** 

Date	Revision	Description of Changes
06-Aug-2004	1	First Release.
02-Sep-2004	2	Complete Version
06-Sep-2005	3	Inserted Ecopack indication

Obsolete Product(s) - Obsolete Product(s)

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